- 23. The method of claim 22, wherein the connecting material includes the structured elements.
- 24. The method of claim 23, wherein the structured elements are mixed in a material comprising flux prior to being combined in the connecting material.
- 25. The method of claim 23, wherein a third electrode is formed on the substrate, and the connecting material generates an electrical connection between the first electrode and the third electrode.
- 26. The method of claim 23, wherein the structured elements make up about 1 to 10% volume content of the connecting material.
- 27. The method of claim 23, wherein the structured elements make up about 2% volume content of the connecting material.
- 28. The method of claim 21, wherein the maximum dimension of the structured elements is determined by screening a sample of structured elements to remove all structured elements having a dimension greater than a predetermined dimension.
- 29. The method of claim 28, wherein screening of the structured elements removes structured elements having a dimension greater than about 25 microns.
- **30**. The method of claim 21, wherein the predetermined dimension is about 20 to 80 microns.
- **31**. The method of claim 22, wherein the first electrode is mounted to the substrate at two separate locations.
- **32**. The method of claim 20, wherein the first electrode is mounted to the substrate at a single location.
- 33. The method of claim 21, further comprising the steps of electrically connecting the first or second electrode to a constant voltage source, and electrically connecting the first or second electrode not electrically connected to the constant voltage source to an amplifier, wherein the change in capacitance relates to a change a current flowing from the constant voltage source to the amplifier.
- **34**. The method of claim 22, wherein the substrate is a printed circuit board with electrical traces formed thereon, and the method further comprises the step of electrically connecting the first and second electrodes to separate traces.
- **35**. The method of claim 21, further comprising the step of forming a dimple in a surface of the first electrode.
- **36.** A capacitive force-based touch sensor assembly, comprising:
  - a frame;
  - a touch sensitive surface; and
  - multiple force activated devices positioned between the touch sensitive surface and the frame for detecting an applied force to the touch sensitive surface due to a touch input, each device comprising:
    - first and second electrodes spaced apart a predetermined distance from each other when in a rest position, a measurable capacitance existing between the first and second electrodes;
    - structured elements having a predetermined maximum dimension positioned between the first and second electrodes to control the predetermined distance;
    - whereby the applied force causes a change in the direction between the first and second electrodes and a related change in the capacitance, and the change in capacitance of each device can be measured to

- determine information related to the location of the touch input to the touch sensitive surface.
- 37. The sensor assembly of claim 36, further comprising a seal membrane that forms a seal between the frame and touch sensitive surface, and the assembly is functional as self-contained unit.
- **38**. The sensor assembly of claim 36, wherein each force activated device is preloaded with a force, and a touch input to the touch sensitive surface unloads the devices.
- **39**. A monitor having force-based touch capabilities, the monitor comprising:
  - a screen; and
  - a force activated device positioned adjacent the screen for detecting an applied force to the screen, the device comprising:
    - first and second electrodes spaced apart a predetermined distance from each other when in a rest position, a measurable capacitance existing between the first and second electrodes;
    - structured elements having a predetermined maximum dimension positioned between the first and second electrodes to control the predetermined distance;
    - whereby the applied force causes a change in the distance between the first and second electrodes and a related change in the capacitance that can be measured to determine information related to the applied force.
- **40**. A connecting material for use in a capacitive device capable of detecting differences in an applied force over a continuous range of applied force including zerio force, the device including opposing first and second electrodes mounted to a substrate and spaced apart a predetermined distance when in a rest state, the sensor having a capacitance controlled by the relative spacing between the first and second electrodes, the connecting material comprising:

curable material; and

- structured elements mixed within the curable material, the structured elements having a predetermined dimension;
- whereby the connecting material is used to mount the first electrode to the substrate to control the predetermined distance with the structured elements.
- **41**. The connecting material of claim 40, wherein the curable material comprises a conductive solder material.
- 42. The connecting material of claim 40, further comprises a flux material, wherein the structured elements are mixed in the flux prior to being combined with the curable materal
- **43**. The connecting material of claim 40, wherein the structured elements are make up no less than about 1% volume content of the connecting material.
- **44**. The connecting material of claim 40, wherein the structured elements are spherical shaped.
- **45**. The connecting material of claim 40, wherein the curable material is an adhesive.
- **46**. The connecting material of claim 40, wherein the structured elements comprising electrically conductive material.

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